

RoHS Recast Compliant

Serial ATA Flash Drive

SU120 M.2 2260 Product Specifications

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Version 1.1



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Features:

- **Standard SATA Interface Compliance**
 - Serial ATA Revision 3.1 compliance
 - SATA 6.0 Gbps interface
 - ATA-8 command set
- **Capacities**
 - 8, 16, 32, 64, 128 GB
- **Performance***
 - Interface burst read/write: 600 MB/sec
 - Sustained read: up to 515 MB/sec
 - Sustained write: up to 180 MB/sec
- **Flash Management**
 - Built-in hardware ECC
 - Static/dynamic wear-leveling
 - Flash bad-block management
 - S.M.A.R.T.
 - Power Failure Management
 - ATA Secure Erase
 - TRIM
- **NAND Flash Type:** MLC
- **Firmware version:** SLC-Lite
- **Endurance**
 - 8 GB: 72 TBW
 - 16 GB: 145 TBW
 - 32 GB: 290 TBW
 - 64 GB: 581 TBW
 - 128 GB: 1,163 TBW
- **Temperature ranges**
 - Operating:
 - Standard: 0°C to 70°C
 - Extended: -40°C to 85°C
 - Storage: -40°C to 85°C
- **Supply voltage**
 - 3.3 V ± 5%
- **Power consumption (typical)***
 - Active mode: 540 mA
 - Idle mode: 100 mA
- **Connector type**
 - 75-pin SATA-based M.2 module pinout
- **Form factor**
 - M.2 2260 form factor
 - Dimensions: 60.00mm x 22.00mm x3.65mm
- **Shock & Vibration*****
 - Shock:1500 G
 - Vibration: 15 G
- **MTBF:** >2,000,000 hours
- **RoHS Recast compliant (complies with 2011/65/EU standard)**
- **Device Sleep mode (optional)**

*Varies from capacities. The values for performances and power consumptions presented are typical and may vary depending on flash configurations or platform settings. The term idle refers to the standby state of the device.

**Non-operating

Table of Contents

| | |
|--|-----------|
| 1. GENERAL DESCRIPTION | 3 |
| 2. PIN ASSIGNMENTS | 3 |
| 3. PRODUCT SPECIFICATIONS..... | 6 |
| 3.1 CAPACITY | 6 |
| 3.2 PERFORMANCE | 6 |
| 3.3 ENVIRONMENTAL SPECIFICATIONS | 7 |
| 3.4 MEAN TIME BETWEEN FAILURES (MTBF)..... | 7 |
| 3.5 CERTIFICATION AND COMPLIANCE | 7 |
| 4. FLASH MANAGEMENT | 8 |
| 4.1 ERROR CORRECTION/DETECTION | 8 |
| 4.2 BAD BLOCK MANAGEMENT | 8 |
| 4.3 WEAR LEVELING | 8 |
| 4.4 POWER FAILURE MANAGEMENT | 8 |
| 4.5 ATA SECURE ERASE | 9 |
| 4.6 TRIM | 9 |
| 4.7 SATA POWER MANAGEMENT | 9 |
| 4.8 SLC-LITE | 9 |
| 4.9 ENDURANCE | 10 |
| 5. SOFTWARE INTERFACE | 11 |
| 5.1 COMMAND SET | 11 |
| 5.2 S.M.A.R.T. | 12 |
| 6. ELECTRICAL SPECIFICATION | 13 |
| 7. PHYSICAL CHARACTERISTICS | 14 |
| 8. PRODUCT ORDERING INFORMATION | 16 |

1. General Description

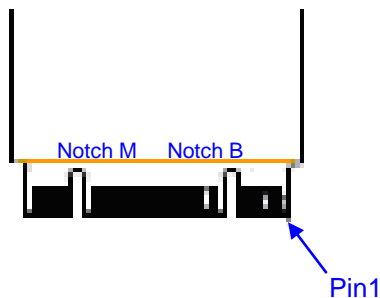
Apacer's SU120-M260 is the next generation modularized Solid State Drive (SSD) with the shape of all new M.2 form factor, aimed to be the more suitable for mobile and compact computers with standard width at only 22.00 mm. SU120-M260 appears in M.2 2260 mechanical dimensions and is believed to be the leading add-in storage solution for future host computing systems.

The M.2 SSD is designed with SATA-based connector pinouts, providing full compliance with the latest SATA Revision 3.1 interface specifications. Aside from SATA compliance, SU120-M260 delivers exceptional performance and power efficiency. On the other hand, the extreme thin and light form factor makes SU120-M260 the ideal choice for mobile computing systems, which appears to be the trend in near future.

Regarding reliability, SU120-M260 is built with a powerful SATA controller that supports on-the-module ECC as well as efficient wear leveling scheme. In terms of power efficiency, SU120-M260 is compliant with SATA 6.0 Gbps interface standard so that it can operate on SATA power management modes, which greatly save on power consumption.

2. Pin Assignments

This connector does not support hot plug capability. There are a total of 75 pins. 12 pin locations are used for mechanical key locations; this allows such a module to plug into both Key B and Key M connectors.



| Pin | Type | Description |
|-----|---------------|--|
| 1 | CONFIG_3 | Ground (according to M.2 configurations for SSD-SATA definition) |
| 2 | 3.3V | Supply Pin, 3.3V |
| 3 | GND | Ground |
| 4 | 3.3V | Supply pin, 3.3V |
| 5 | No connect | No connect |
| 6 | Not available | No connect (used for other purposes) |
| 7 | Not available | No connect (used for other purposes) |
| 8 | Not available | No connect (used for other purposes) |
| 9 | No connect | No connect |

M.2 2260 Flash Drive APM2T60P200xxxxAN-XTMX

| | | |
|----|---------------|--|
| 10 | DAS/DSS | Device Activity Signal/Disable Staggered Spin-up |
| 11 | No connect | No connect (used for other purposes) |
| 12 | Module key | Mechanical notch B |
| 13 | Module key | Mechanical notch B |
| 14 | Module key | Mechanical notch B |
| 15 | Module key | Mechanical notch B |
| 16 | Module key | Mechanical notch B |
| 17 | Module key | Mechanical notch B |
| 18 | Module key | Mechanical notch B |
| 19 | Module key | Mechanical notch B |
| 20 | Not available | No connect (used for other purposes) |
| 21 | CONFIG_0 | Ground (according to M.2 configurations for SSD-SATA definition) |
| 22 | Not available | No connect (used for other purposes) |
| 23 | Not available | No connect (used for other purposes) |
| 24 | Not available | No connect (used for other purposes) |
| 25 | Not available | No connect (used for other purposes) |
| 26 | Not available | No connect (used for other purposes) |
| 27 | GND | Ground |
| 28 | Not available | No connect (used for other purposes) |
| 29 | Not available | No connect |
| 30 | Not available | No connect (used for other purposes) |
| 31 | Not available | No connect |
| 32 | Not available | No connect (used for other purposes) |
| 33 | GND | Ground |
| 34 | Not available | No connect (used for other purposes) |
| 35 | Not available | No connect |
| 36 | Not available | No connect (used for other purposes) |
| 37 | Not available | No connect |
| 38 | Not available | No connect |
| 39 | GND | Ground |
| 40 | Not available | No connect (used for other purposes) |
| 41 | SATA-Rx+ | Host receiver differential signal pair |
| 42 | Not available | No connect (used for other purposes) |
| 43 | SATA-Rx- | Host receiver differential signal pair |
| 44 | Not available | No connect (used for other purposes) |
| 45 | GND | Ground |
| 46 | Not available | No connect (used for other purposes) |

M.2 2260 Flash Drive APM2T60P200xxxxAN-XTMX

| | | |
|----|------------------------|---|
| 47 | SATA-Tx- | Host transmitter differential pair |
| 48 | Not available | No connect (used for other purposes) |
| 49 | SATA-Tx+ | Host transmitter differential pair |
| 50 | Not available | No connect |
| 51 | GND | Ground |
| 52 | Not available | Not used |
| 53 | Not available | Not used |
| 54 | Not available | Not used |
| 55 | Not available | Not used |
| 56 | Reserved for MFG Data | Manufacturing Data line. Used for SSD manufacturing only. Not used in normal operation. Pins should be left N/C in platform Socket. |
| 57 | GND | Ground |
| 58 | Reserved for MFG clock | Manufacturing Clock line. Used for SSD manufacturing only. Not used in normal operation. Pins should be left N/C in platform Socket |
| 59 | Module key | Mechanical notch M |
| 60 | Module key | Mechanical notch M |
| 61 | Module key | Mechanical notch M |
| 62 | Module key | Mechanical notch M |
| 63 | Module key | Mechanical notch M |
| 64 | Module key | Mechanical notch M |
| 65 | Module key | Mechanical notch M |
| 66 | Module key | Mechanical notch M |
| 67 | Not available | No connect (used for other purposes) |
| 68 | SUSCLK | 32 kHz clock supply input that is provided by PCH to reduce power and cost for the module |
| 69 | CONFIG_1 | Defines module type |
| 70 | 3.3V | Supply pin, 3.3V |
| 71 | GND | Ground |
| 72 | 3.3V | Supply pin, 3.3V |
| 73 | GND | Ground |
| 74 | 3.3V | Supply pin, 3.3V |
| 75 | CONFIG_2 | Ground |

3. Product Specifications

3.1 Capacity

Capacity specification of SU120-M260 is available as shown in Table 3-1. It lists the specific capacity and the default numbers of heads, sectors and cylinders for each product line.

Table 3-1: Capacity specifications

| Capacity | Total Bytes | Cylinders | Heads | Sectors | Max LBA |
|----------|-----------------|-----------|-------|---------|-------------|
| 8 GB | 8,012,390,400 | 15,525 | 16 | 63 | 15,649,200 |
| 16 GB | 16,013,942,784 | 16,383 | 16 | 63 | 31,277,232 |
| 32 GB | 32,017,047,552 | 16,383 | 16 | 63 | 62,533,296 |
| 64 GB | 64,023,257,088 | 16,383 | 16 | 63 | 125,045,424 |
| 128 GB | 128,035,676,160 | 16,383 | 16 | 63 | 250,069,680 |

*Display of total bytes varies from file systems, which means not all of the bytes can be used for storage.

**Notes: 1 GB = 1,000,000,000 bytes; 1 sector = 512 bytes.

LBA count addressed in the table above indicates total user storage capacity and will remain the same throughout the lifespan of the device. However, the total usable capacity of the SSD is most likely to be less than the total physical capacity because a small portion of the capacity is reserved for device maintenance usages.

3.2 Performance

Performances of SU120-M260 are listed below in table 3-2.

Table 3-2: Performance

| Capacity | 8 GB | 16 GB | 32 GB | 64 GB | 128 GB |
|-------------------------------|------|-------|-------|-------|--------|
| Performance | | | | | |
| Sustained read (MB/s) | 300 | 510 | 515 | 515 | 515 |
| Sustained write (MB/s) | 170 | 180 | 180 | 180 | 180 |

Note: Results were measured by CrystalDiskMark and may differ from various flash configurations or host system setting

3.3 Environmental Specifications

Environmental specification of SU120-M260 series follows MIL-STD-810 standards as shown in Table 3-3.

Table 3-3 SU120-M260 environmental specifications

| Item | Specification |
|---------------------------|--|
| Operating temperature | 0°C~70°C (standard); -40°C~85°C (extended) |
| Non-operating temperature | -40°C~85°C |
| Operating humidity | 40°C, 90%RH |
| Non-operating humidity | 40°C, 93%RH |
| Vibration (Non-operating) | Frequency/Displacement: 20Hz~80Hz/1.52mm Frequency/Acceleration: 80Hz~2000Hz/20G X, Y, Z axis/60mins |
| shock (Non-operating) | 1500G, 0.5ms |
| Drop (Non-operating) | 80cm free fall, 6 face of each unit |
| Bending (non-operating) | ≥20N, hold 1min/5times |
| Torque (non-operating) | 0.5N-m or ±2.5 deg, hold 1min/5times |
| ESD (Electrostatic) | Passed (at relative temp/humidity: 24°C, 49%RH) |

3.4 Mean Time Between Failures (MTBF)

Mean Time Between Failures (MTBF) is predicted based on reliability data for the individual components in SU120-M260. The prediction result for SU120-M260 is more than 2,000,000 hours.

Notes about the MTBF:

The MTBF is predicated and calculated based on "Telcordia Technologies Special Report, SR-332, Issue 2" method.

3.5 Certification and Compliance

SU120-M260 complies with the following standards:

- CE: EN55022
- FCC :CISPR22
- BSMI 13438
- RoHS Recast

4. Flash Management

4.1 Error Correction/Detection

SU120-M260 implements a hardware ECC scheme, based on the BCH algorithm. It can detect and correct up to 72 bits error in 1K bytes.

4.2 Bad Block Management

Bad blocks are blocks that include one or more invalid bits, and their reliability is not guaranteed. Blocks that are identified and marked as bad by the manufacturer are referred to as “Initial Bad Blocks”. Bad blocks that are developed during the lifespan of the flash are named “Later Bad Blocks”. Apacer implements an efficient bad block management algorithm to detect the factory-produced bad blocks and manages any bad blocks that appear with use. This practice further prevents data being stored into bad blocks and improves the data reliability.

4.3 Wear Leveling

NAND flash devices can only undergo a limited number of program/erase cycles, and in most cases, the flash media are not used evenly. If some areas get updated more frequently than others, the lifetime of the device would be reduced significantly. Thus, Wear Leveling is applied to extend the lifespan of NAND flash by evenly distributing write and erase cycles across the media.

Apacer provides advanced Wear Leveling algorithm, which can efficiently spread out the flash usage through the whole flash media area. Moreover, by implementing both dynamic and static Wear Leveling algorithms, the life expectancy of the NAND flash is greatly improved.

4.4 Power Failure Management

Power Failure Management is a mechanism to prevent data loss during unexpected power failure. DRAM is a volatile memory and frequently used as temporary cache or buffer between the controller and the NAND flash to improve the SSD performance. However, one major concern of the DRAM is that it is not able to keep data during power failure. Accordingly, SU120-M260 applies the flush mechanism, which requests the controller to transfer data to the cache. For SU120-M260, DDR performs as a cache. Only when the data is fully committed to the NAND flash will the controller send acknowledgement (ACK) to the host. Such implementation can prevent false-positive performance and the risk of power cycling issues.

Additionally, it is critical for a controller to shorten the time the in-flight data stays in the cache. Thus, SU120-M260 applies an algorithm to reduce the amount of data resides in the cache to provide a better performance. This algorithm allows incoming data to only have a “pit stop” in the cache and then move to the NAND flash at once. If the flash is jammed due to particular file sizes (such as random 4KB data), the cache will be treated as an “organizer”, consolidating incoming data into groups before written into the flash to improve write amplification.

In sum, Power Failure Management proves to provide the reliability required by consumer, industrial, and enterprise-level applications.

4.5 ATA Secure Erase

ATA Secure Erase is a standard ATA command and will write all “0xFF” to fully wipe all the data on hard drives and SSDs. When this command is issued, the SSD controller will empty its storage blocks and return to its factory default settings.

4.6 TRIM

TRIM is a feature which helps improve the read/write performance and speed of solid-state drives (SSD). Unlike hard disk drives (HDD), SSDs are not able to overwrite existing data, so the available space gradually becomes smaller with each use. With the TRIM command, the operating system can inform the SSD which blocks of data are no longer in use and can be removed permanently. Thus, the SSD will perform the erase action, which prevents unused data from occupying blocks all the time.

4.7 SATA Power Management

By complying with SATA 6.0 Gb/s specifications, the SSD supports the following SATA power saving modes:

- ACTIVE: PHY ready, full power, Tx & Rx operational
- PARTIAL: Reduces power, resumes in under 10 μ s (microseconds)
- SLUMBER: Reduces power, resumes in under 10 ms (milliseconds)
- HIPM: Host-Initiated Power Management
- DIPM: Device-Initiated Power Management
- Device Sleep (DevSleep or DEVSLP): PHY powered down; power consumption \leq 5 mW; host assertion time \leq 10 ms; exit timeout from this state \leq 20 ms (unless specified otherwise in SATA Identify Device Log).

Note:

1. The behaviors of power management features would depend on host/device settings.

4.8 SLC-Lite

To achieve SLC-like performance and endurance, cell distribution management for MLC is necessary in order to greatly adjust the voltage delta and charge sensing. By programming only the least significant bit (LSB), the cell distribution behaves almost identical to that of SLC flash. This highly improves the precision of delta and the threshold voltage of each cell. Thus, the MLC performance and endurance, especially in P/E cycles, will be escalating by multiplies, to the level almost on par with SLC. In this case, users would get all the benefits of both the quality and the cost.

4.9 Endurance

The endurance of a storage device is predicted by TeraBytes Written based on several factors related to usage, such as the amount of data written into the drive, block management conditions, and daily workload for the drive. Thus, key factors, such as Write Amplifications and the number of P/E cycles, can influence the lifespan of the drive.

| Capacity | TeraBytes Written |
|----------|-------------------|
| 8 GB | 72 |
| 16 GB | 145 |
| 32 GB | 290 |
| 64 GB | 581 |
| 128 GB | 1,163 |

Notes:

- The measurement assumes the data written to the SSD for test is under a typical and constant rate.
- The measurement follows the standard metric: 1 TB (Terabyte) = 1000 GB.
- This estimation complies with JEDEC JESD-219, enterprise endurance workload of random data with payload size distribution.

5. Software Interface

5.1 Command Set

Table 5-1: Command set

| Command | Code | Command | Code |
|-----------------------------------|---------|---------------------------|------|
| Data Set Management | 06h | CHECK POWER MODE | 98h |
| Recalibrate | 10h-1Fh | SLEEP | 99h |
| Read Sectors | 20h | SMART | B0h |
| Read Sectors without Retry | 21h | DEVICE CONFIGURATION | B1h |
| Read Sectors EXT | 24h | Read Multiple | C4h |
| Read DMA EXT | 25h | Write Multiple | C5h |
| Read Native Max Address EXT | 27h | Set Multiple Mode | C6h |
| Read Multiple EXT | 29h | Read DMA | C8h |
| Read Log EXT | 2Fh | Read DMA without Retry | C9h |
| Write Sectors | 30h | Write DMA | CAh |
| Write Sectors without Retry | 31h | Write DMA without Retry | CBh |
| Write Sectors EXT | 34h | Write Multiple FUA EXT | CEh |
| Write DMA EXT | 35h | Standby Immediate | E0h |
| Set Native Max Address EXT | 37h | Idle Immediate | E1h |
| CFA WRITE SECTORS WITHOUT ERASE | 38h | Standby | E2h |
| Write Multiple EXT | 39h | IDLE | E3h |
| Write DMA FUA EXT | 3Dh | Read Buffer | E4h |
| Write Long EXT | 3Fh | Check Power Mode | E5h |
| Read Verify Sectors | 40h | Sleep | E6h |
| Read Verify Sectors without Retry | 41h | Flush Cache | E7h |
| Read Verify Sectors EXT | 42h | Write Buffer | E8h |
| WRITE UNCORRECTABLE EXT | 45h | Flush Cache EXT | EAh |
| Read FPDMA Queued | 60h | Identify Device | ECh |
| Write FPDMA Queued | 61h | Set Features | EFh |
| Seek | 70h-71h | Security Set Password | F1h |
| Execute Device Diagnostic | 90h | Security Unlock | F2h |
| Initialize Device Parameters | 91h | Security Erase Prepare | F3h |
| Download Microcode | 92h | Security Erase Unit | F4h |
| DOWNLOAD MICROCODE DMA | 93h | Security Freeze Lock | F5h |
| STANDBY IMMEDIATE | 94h | Security Disable Password | F6h |

M.2 2260 Flash Drive
APM2T60P200xxxxAN-XTMX



| | | | |
|----------------|-----|-------------------------|----|
| IDLE IMMEDIATE | 95h | Read Native Max Address | F8 |
| STANDBY | 96h | Set Max Address | F9 |
| IDLE | 97h | | |

5.2 S.M.A.R.T.

SMART, an acronym for Self-Monitoring, Analysis and Reporting Technology, is an open standard that allows a hard disk drive to automatically detect its health and report potential failures. When a failure is recorded by SMART, users can choose to replace the drive to prevent unexpected outage or data loss. Moreover, SMART can inform users of impending failures while there is still time to perform proactive actions, such as copy data to another device.

6. Electrical Specification

Table 6-1: Operating range

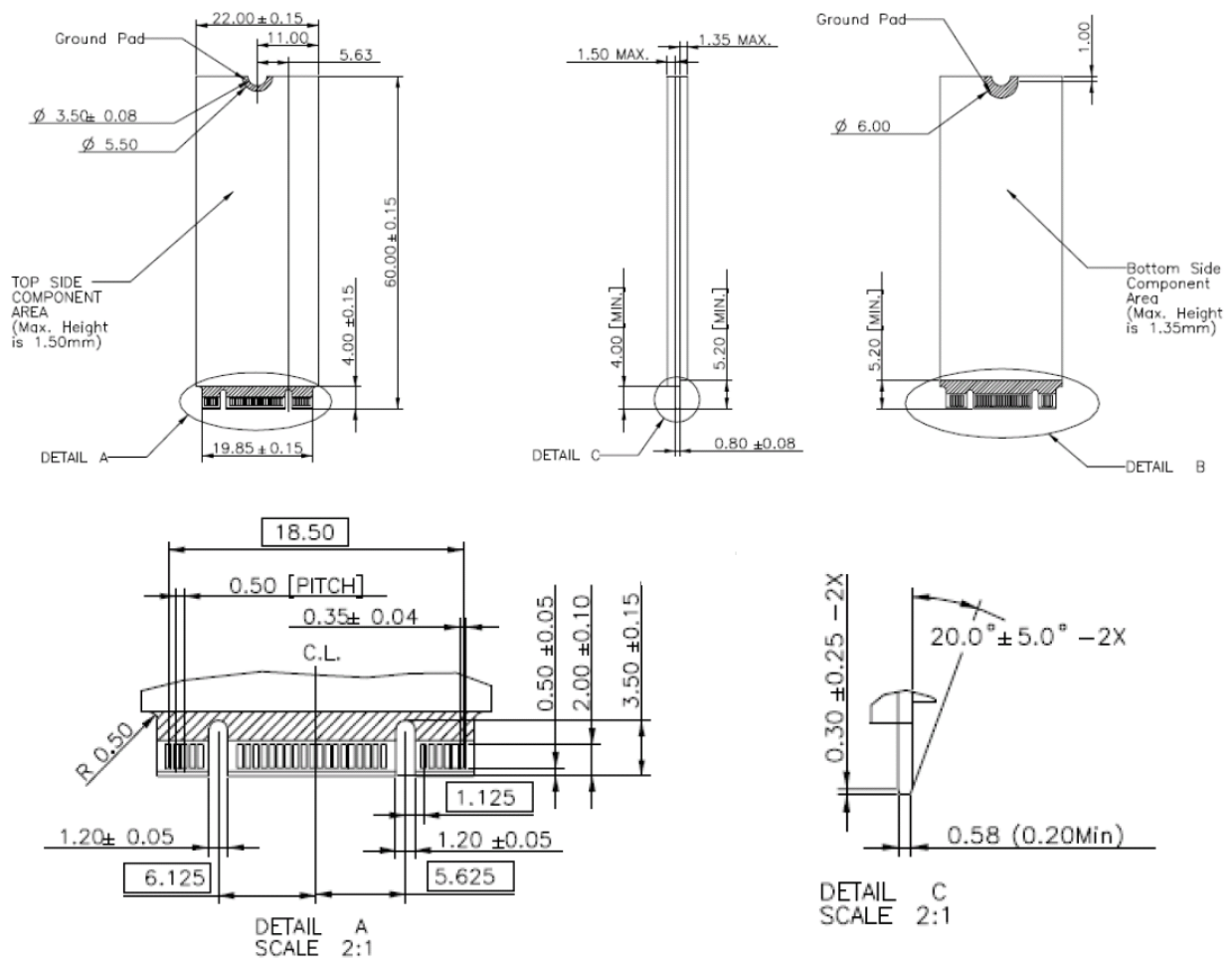
| | |
|----------------------------|---|
| Ambient Temperature | 0°C ~ +70°C(standard) -40°C ~85°C (extended) |
| Supply Voltage | 3.3V±5% (3.135-3.465V) |

Table 6-2: Power consumption (typical)

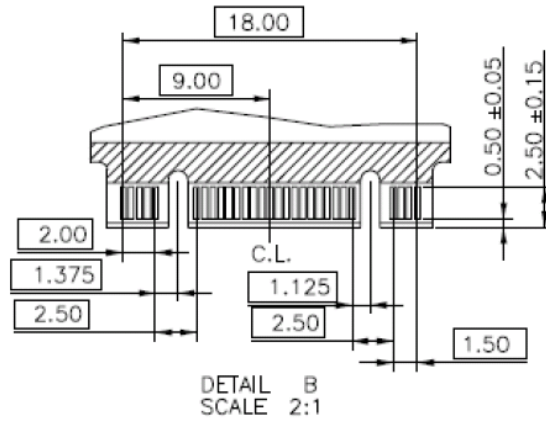
| Modes \ Capacity | 8 GB | 16 GB | 32 GB | 64 GB | 128 GB |
|-------------------------|-------------|--------------|--------------|--------------|---------------|
| Active (mA) | 355 | 350 | 540 | 530 | 530 |
| Idle (mA) | 85 | 85 | 90 | 90 | 90 |

Note: Results may differ from various flash configurations or host system setting

7. Physical Characteristics

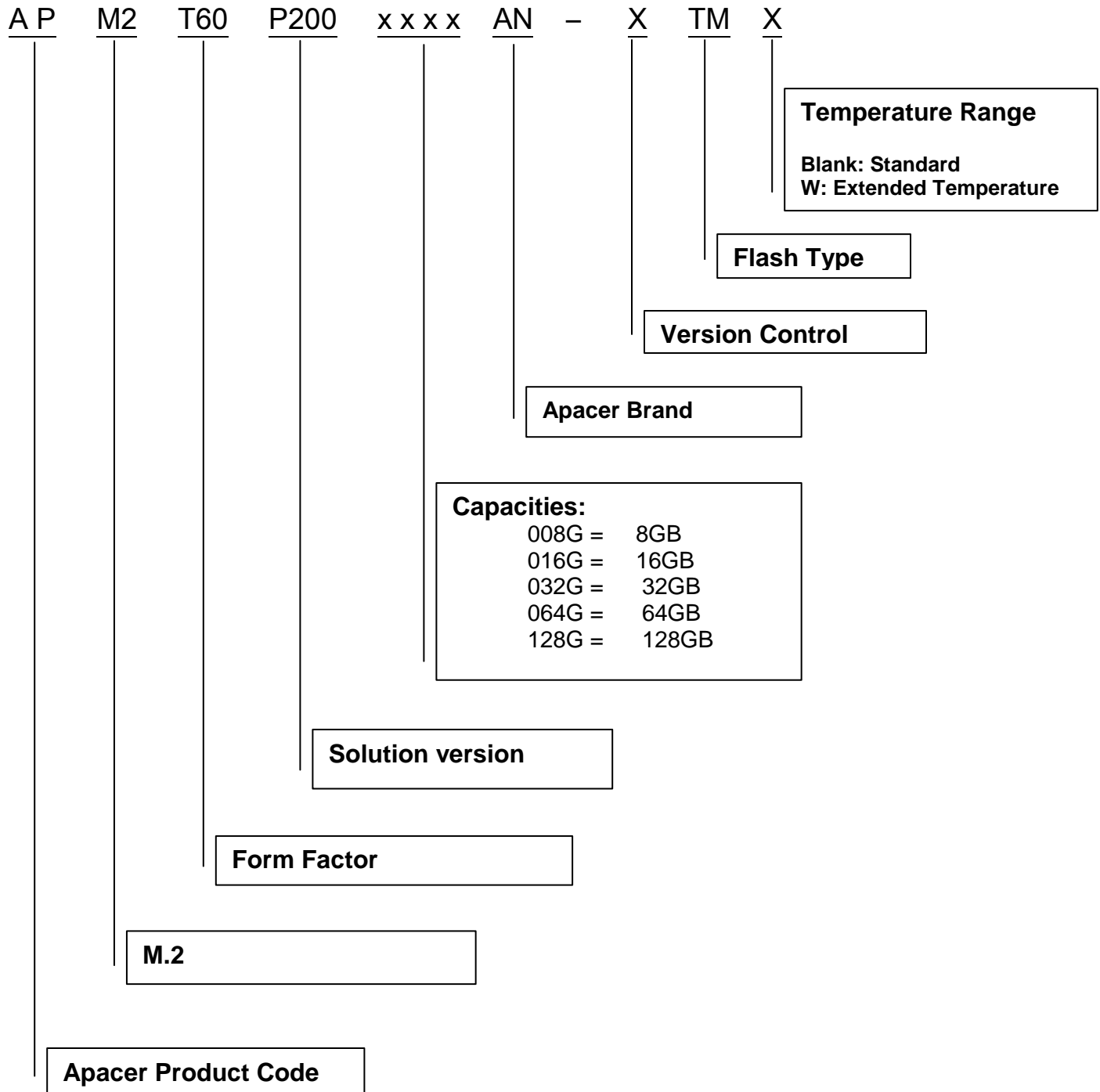


M.2 2260 Flash Drive
APM2T60P200xxxxAN-XTMX



8. Product Ordering Information

8.1 Product Code Designations



8.2 Valid Combinations

8.2.1 Standard Temperature

| Capacity | No DEVSLP | DEVSLP |
|----------|-----------------------|-----------------------|
| 8GB | APM2T60P200008GAN-LTM | APM2T60P200008GAN-MTM |
| 16GB | APM2T60P200016GAN-LTM | APM2T60P200016GAN-MTM |
| 32GB | APM2T60P200032GAN-LTM | APM2T60P200032GAN-MTM |
| 64GB | APM2T60P200064GAN-LTM | APM2T60P200064GAN-MTM |
| 128GB | APM2T60P200128GAN-LTM | APM2T60P200128GAN-MTM |

8.2.2 Extended Temperature

| Capacity | No DEVSLP | DEVSLP |
|----------|------------------------|------------------------|
| 8GB | APM2T60P200008GAN-LTMW | APM2T60P200008GAN-MTMW |
| 16GB | APM2T60P200016GAN-LTMW | APM2T60P200016GAN-MTMW |
| 32GB | APM2T60P200032GAN-LTMW | APM2T60P200032GAN-MTMW |
| 64GB | APM2T60P200064GAN-LTMW | APM2T60P200064GAN-MTMW |
| 128GB | APM2T60P200128GAN-LTMW | APM2T60P200128GAN-MTMW |

Note: Valid combinations are those products in mass production or will be in mass production. Consult your Apacer sales representative to confirm availability of valid combinations and to determine availability of new combinations.

Revision History

| Revision | Date | Description | Remark |
|----------|------------|-----------------------------|--------|
| 1.0 | 06/08/2015 | Official release | |
| 1.1 | 07/07/2015 | Added endurance information | |

Global Presence

| | |
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